



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/724,648	12/01/2003	Pierre Fazan	211.001-D3-US	2320
7590	01/21/2005		EXAMINER LOUIE, WAI SING	
Neil Steinberg Steinberg & Whitt, LLP Suite 1150 2665 Marine Way Mountain View, CA 94043			ART UNIT 2814	
DATE MAILED: 01/21/2005				

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary

Application No.

10/724,648

Applicant(s)

FAZAN ET AL.

Examiner

Wai-Sing Louie

Art Unit

2814

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 27 August 2004.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 28-64 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 28-64 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☐ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date _____.
- 4) ☐ Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____.
- 5) ☐ Notice of Informal Patent Application (PTO-152)
- 6) ☐ Other: _____.

DETAILED ACTION

Double Patenting

The nonstatutory double patenting rejection is based on a judicially created doctrine grounded in public policy (a policy reflected in the statute) so as to prevent the unjustified or improper timewise extension of the "right to exclude" granted by a patent and to prevent possible harassment by multiple assignees. See *In re Goodman*, 11 F.3d 1046, 29 USPQ2d 2010 (Fed. Cir. 1993); *In re Longi*, 759 F.2d 887, 225 USPQ 645 (Fed. Cir. 1985); *In re Van Ornum*, 686 F.2d 937, 214 USPQ 761 (CCPA 1982); *In re Vogel*, 422 F.2d 438, 164 USPQ 619 (CCPA 1970); and, *In re Thorington*, 418 F.2d 528, 163 USPQ 644 (CCPA 1969).

A timely filed terminal disclaimer in compliance with 37 CFR 1.321(c) may be used to overcome an actual or provisional rejection based on a nonstatutory double patenting ground provided the conflicting application or patent is shown to be commonly owned with this application. See 37 CFR 1.130(b).

Effective January 1, 1994, a registered attorney or agent of record may sign a terminal disclaimer. A terminal disclaimer signed by the assignee must fully comply with 37 CFR 3.73(b).

Claims 28-64 are provisionally rejected under the judicially created doctrine of obviousness-type double patenting as being unpatentable over claims 28-63 of copending Application No. 10/724,377. Although the conflicting claims are not identical, they are not patentably distinct from each other because:

With regard to claim 28, Application No. 10/724,377 discloses a semiconductor memory array comprising:

a plurality of memory cells arranged in a matrix of rows and columns, the plurality of memory cells include a first memory cell and second memory cell, where the first and second memory cells each include at least a transistor to constitute the memory cell (claim 28) and where the transistor includes:

- a source region (claim 28);
- a drain region (claim 28);

- a body region disposed between and adjacent to the source region and the drain region, where the body region is electrically floating (claim 28);
- a gate disposed over the body region (claim 28), where the memory cell includes:
 - a first data state representatives of a first charge in the body region (claim 28),
 - a second data state representatives of a second charge in the body region, where the second charge is substantially provided by removing charge from the body region through the source region (claim 28), where the source region of the transistor of the first memory cell and the source region of the transistor of the second memory cell are the same region (claim 28).

With regard to claim 29, in addition to the limitations disclosed in claim 28 above, Application No. 10/724,377 also discloses:

- a gate spaced apart from, and capacitively of a first charge in the body region (claim 50).

With regard to claim 30, Application No. 10/724,377 discloses a control unit, coupled to the gate and the drain region of the transistor of the first memory cell, to provide control signals to transistor of the first memory cell, in response the a first write control signals stores the first charge in the body region and where the first charge is comprised of an accumulation of majority carriers in the body region (claims 29-30).

With regard to claim 31, Application No. 10/724,377 discloses the majority carriers accumulate in a portion of the body region that is adjacent to the source region of the transistor

of the first memory cell and where the source region of the transistor of the first and second memory cell are connected to a fixed voltage (claims 31 and 35).

With regard to claim 32, Application No. 10/724,377 discloses a control unit, coupled to the gate and the drain region of the transistor of the first memory cell, where the transistor of the first memory cell, in response to a second write control signals, stores the second charge in the body region where the second charge is substantially provided by removing charge from the body region through the source region (claim 32).

With regard to claim 33, Application No. 10/724,377 discloses the second write control signals include at least first and second signals, each having positive voltages, where the first signal is applied to the drain region of the transistor of the first memory cell and the second signal is applied to the gate of the transistor of the first memory cell (claim 33).

With regard to claims 34, 45, and 64, Application No. 10/724,377 discloses the memory array further including:

- a reading unit, coupled to the drain region of the transistor of the first memory cell, to determine the data state of the transistor of the first memory cell (claim 34);
- a control unit, coupled to gate of the transistor of the first memory cell, to provide control signals to the transistor of the first memory cell, where in response to a read control signal applied to the gate of the transistor of the first memory cell, the reading unit determines the charge stored in the body region of the transistor of the first memory cell (claim 34).

With regard to claims 35-36 and 50, Application No. 10/724,377 discloses a semiconductor memory array comprising:

- a plurality of memory cells arranged in a matrix of rows and columns, the plurality of memory cell include a first memory cell and a second memory cell, where the first and second memory cells each include at least a transistor to constitute the memory cell where the transistor includes:
 - a source region having impurities to provide a first conductivity type (claim 36);
 - a drain region having impurities to provide a first conductivity type (claim 36);
 - a body region disposed between and adjacent to the source region and the drain region, where the body region is electrically floating and includes impurities to provide a second conductivity type where the second conductivity type is different from the first conductivity type (claim 36);
 - a gate disposed over the body region (claim 1), where the memory cell includes:
 - a first data state representatives of a first charge in the body region where the first charge is substantially provided by impact ionization (claim 36),
 - a second data state representatives of a second charge in the body region, where the second charge is substantially provided by removing charge from the body region through the source region

where the source region of the transistor of the first memory cell and the source region of the transistor of the second memory cell are the same region (claim 36).

With regard to claims 37 and 46, Application No. 10/724,377 discloses a control unit, coupled to the gate and drain region of the transistor of the first memory cell, to apply control signals to the transistor of the first memory cell where the control signals include first write control signals to accumulate the first charge in the body of the transistor of the first memory cell and a second write control signals to provide the second charge in the body region by removing charge from the body region through the source region of the transistor of the first memory cell (claim 37).

With regard to claim 38, Application No. 10/724,377 discloses the first charge is stored in the body region of the transistor of the first memory cell in response to applying a first signal, having a first negative voltage, to the drain region and a second signal, having a second negative voltage, to the gate of the transistor of the first memory cell (claim 38).

With regard to claims 39 and 59, Application No. 10/724,377 discloses the transistor of the first memory cell stores at least a substantial portion of the first charge in a portion of the body region of the transistor of the first memory cell that is adjacent to the source region of the transistor of the first memory cell (claim 39).

With regard to claims 40, 47, and 60, Application No. 10/724,377 discloses the second write control signals include a first signal, having a first positive voltage, applied to the drain region of the transistor of the first memory cell and a second signal, having a second positive voltage, applied to the gate of the transistor of the first memory cell (claim 40).

With regard to claim 41, Application No. 10/724,377 discloses the source regions of the transistors of the first and second memory cells are connected to a fixed voltage (claim 35).

With regard to claims 42 and 61, Application No. 10/724,377 discloses the second charge is stored in the body region in response to removing the first positive voltage from the drain region of the transistor of the first memory cell before removing the second positive voltage from the gate of the transistor of the first memory cell (claim 42).

With regard to claims 43, 48, and 62 Application No. 10/724,377 discloses in response to the first and second positive voltages, the transistor of the first memory cell includes a forward bias current between its body region and its source region (claim 43).

With regard to claims 44, 49, and 63, Application No. 10/724,377 discloses the second charge is stored in the body region of the transistor of the first memory cell in response to removing the first positive voltage from the drain region of the transistor of the first memory cell and the second positive voltage from the gate of the transistor of the first memory cell (claim 44).

With regard to claim 51, Application No. 10/724,377 does not disclose the plurality of memory cells includes a third memory cell where the third memory cell includes at least a transistor to constitute the memory cell. However, duplication of parts was held to have been obvious. *St. Regis Paper Co. v. Beemis Co. Inc.* 193 USPQ 8, 11 (1977); *In re Harza* 124 USPQ 378 (CCPA 1960). Therefore, it would have been obvious for the one with ordinary skill in the art to a third memory cell in the plurality of memory cells.

With regard to claim 52, Application No. 10/724,377 discloses a control unit, coupled to the transistor of the first memory cell, to control the data state of the first memory cell where, in response to a first voltage applied to the drain region of the transistor of the first memory cell and

a second voltage applied to the gate of the transistor of the first memory cell, the first charge is removed from the body region of the transistor of the first memory cell through its source region (claim 51).

With regard to claim 53, Application No. 10/724,377 discloses the control unit, in response to removing the first voltage from the drain region of the transistor of the first memory cell before removing the second voltage from the gate of the transistor of the first memory cell, causes the second charge to be stored in the body region of the transistor of the first memory cell (claim 52).

With regard to claim 54, Application No. 10/724,377 discloses the control unit, in response to applying ground to the drain region of the transistor of the first memory cell before removing the second voltage from the gate of the transistor of the first memory cell, causes the second charge to be stored in the body region of the transistor of the first memory cell (claim 53).

With regard to claim 55, Application No. 10/724,377 discloses the control unit, in response to applying a third voltage to the drain region of the transistor of the first memory cell before applying a fourth voltage to the gate of the transistor of the first memory cell, causes the transistor of the first memory cell to store the second charge in its body region (claim 54).

With regard to claim 56, Application No. 10/724,377 discloses the transistor of the first memory cell stores the first charge in a portion of its body region that is adjacent to its source region (claim 55).

With regard to claim 57, Application No. 10/724,377 discloses a control unit, coupled to the gate and the drain region of the transistor of the first memory cell, to apply control signals to transistor of the first memory cell where:

- in response to a first write control signals, the transistor of the first memory cell generates and stores the first charge in the body region (claim 56);
- in response to a second write control signals, the transistor of the first memory cell generates and stores the second charge in the body region where the transistor of the first memory cell generates the second charge by removing charge from its body region through its source region (claim 56), where the first and second write control signals each include a plurality of signals (claim 56).

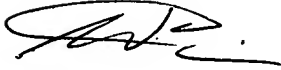
With regard to claim 58, Application No. 10/724,377 discloses the first write control signals include a first signal having a first negative voltage to the drain and a second signal having a second negative voltage to the gate and where, in response to the first and second negative voltages, the first charge is stored in the body region of the transistor of the first memory cell (claim 57).

This is a provisional obviousness-type double patenting rejection because the conflicting claims have not in fact been patented.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Wai-Sing Louie whose telephone number is (571) 272-1709. The examiner can normally be reached on 7:30 AM to 4:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Wsl 
January 15, 2005.